Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/709,823	CHANG CHIEN ET AL.	
Examiner	Art Unit	
Tanh Q. Nguyen	2182	

	SEARCHED  Class Subclass Date Examiner		
Class	Subclass	Date	Examiner
710	62-64,72-74 100,300,305 306,311,313	05/04/07	TON
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INT	INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH		)
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